


<b>Search Notes</b>  	<b>Application/Control No.</b>  10812010	<b>Applicant(s)/Patent Under Reexamination</b>  CHUNG ET AL.
	<b>Examiner</b>  Wendmagegn, Girumsew	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner
386	95	6/20/2008	gw
386	124	6/20/2008	gw
386	125	6/20/2008	gw

SEARCH NOTES		
Search Notes	Date	Examiner
US-PGPUB;USPAT;USOCR;EPO;JPO;DERWENT;IBM_TDB	6/12/2008	gw
Consulted Thai Tran	12/17/2007	gw
Inventor(s) search	6/20/2008	gw

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner